Seminar: Digital Circuit Testing and Design for Testability

Electrical & Electronics Engineering Department

Invites you to a

SEMINAR

"Digital Circuit Testing and Design for Testability"

by

Dr. Afaq Ahmad

Sunday, 07 May, 1995
College of Engineering Conference Room
12:00-1:00 PM
Highlights

- Introduction
  - Testing
  - Need for testing
  - Level of testing
  - Cost of testing
  - Roles of testing

- Test Generation
- Response Data Compression
- Testability Analysis
- Design for Testability Basics
- Moving Towards Built In Test
- Research Areas
- Concluding Remarks